



A New Real-Time Quantum Efficiency Measurement System

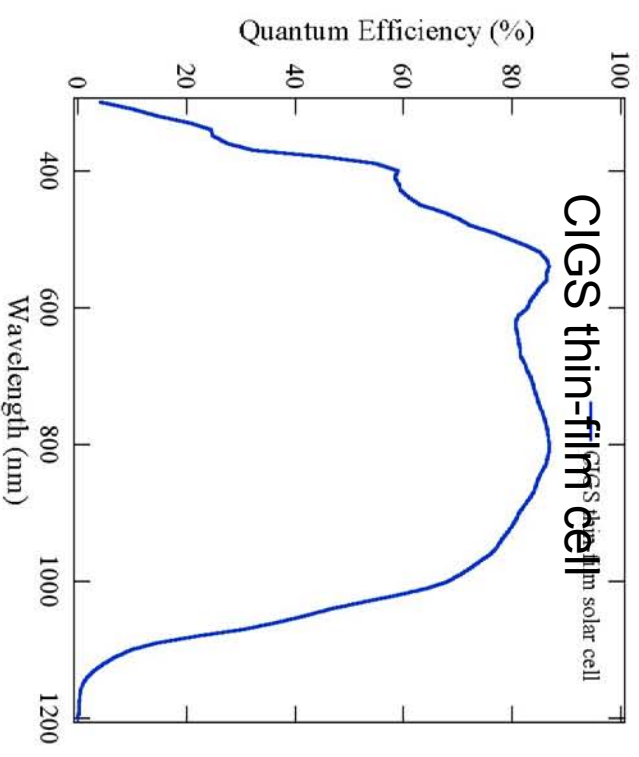
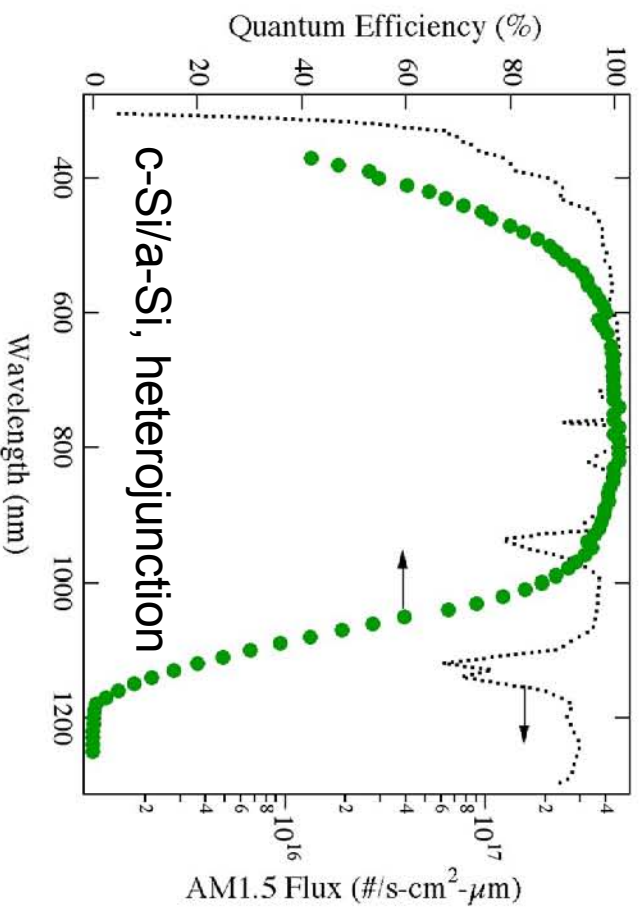
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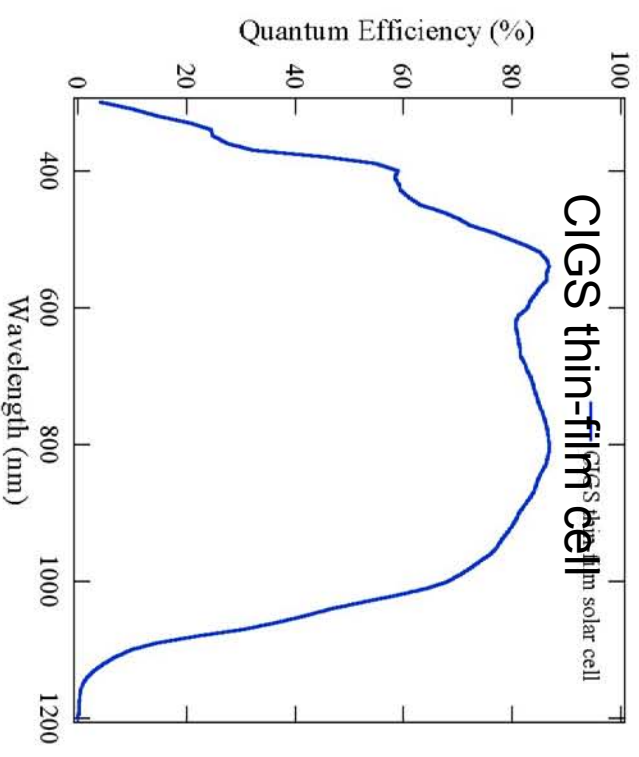
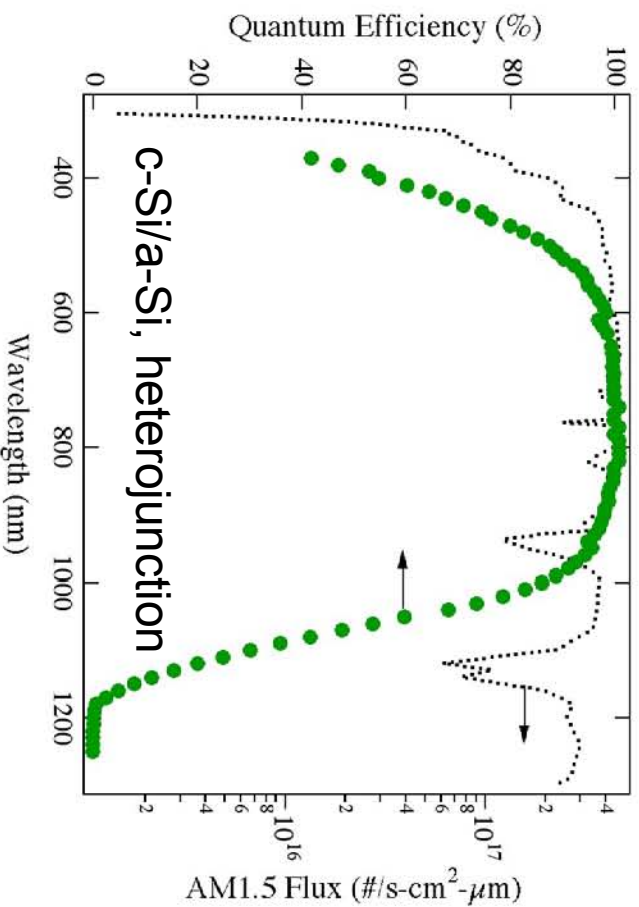
Presented at the 33rd IEEE Photovoltaic Specialist Conference held May 11-16, 2008 in San Diego, California

Information-Rich Quantum Efficiency Graphs



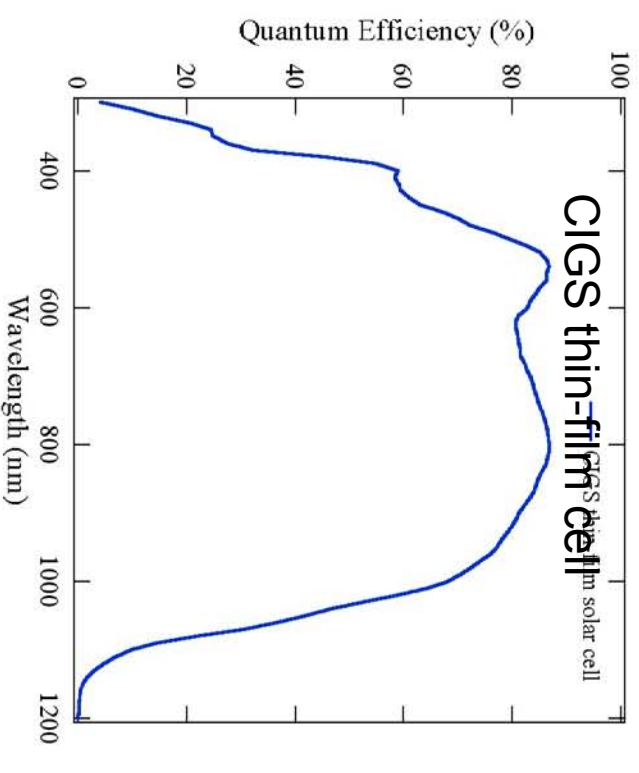
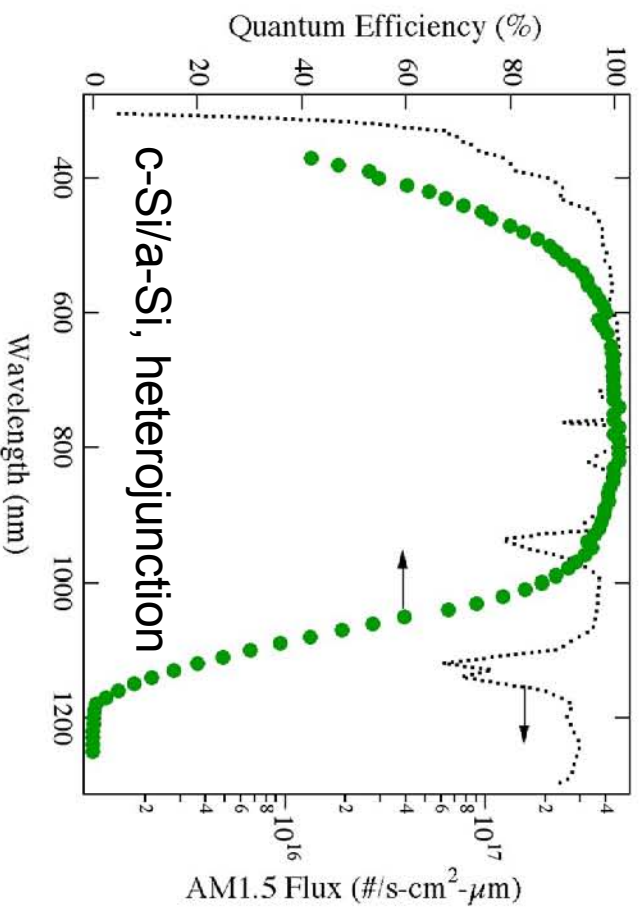
- Spectral response (current loss)
- Spatial response
 - “Blue” – front, “Red” - back surfaces, bulk
 - thin-film layers (thickness, composition, Bandgap)
- Diffusion length (modeling) (Kieliba, JAP 2006)
- Recombination centers (QE(T)) (Wagner,APL 2003)
- Junction physics, impurity diffusion (QE(V)) (Batzner TSF 2003),(a-Si:H cells)

Information-Rich Quantum Efficiency Graphs



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- ZnO CdS Bandgap
- ZnO:Al

So, why don't we use QE graphs more in research and industry?

Traditional QE method

Time!

(money, lack of graduate students)

New method



chopper

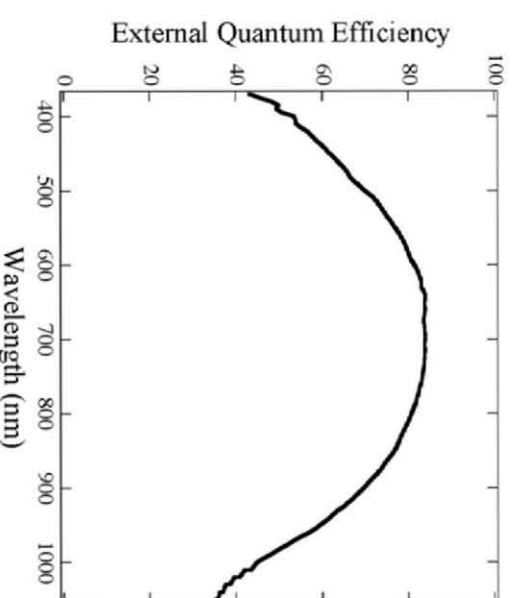
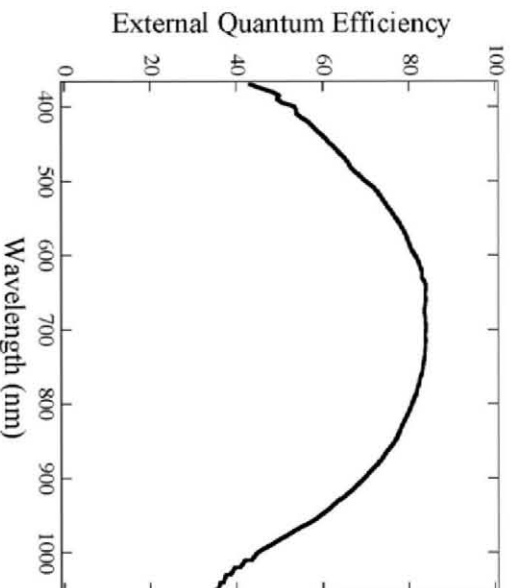
Lock-in Amp.



Parallel measurement ~ 0.1 sec



Serial measurement ~ 5-20 mins

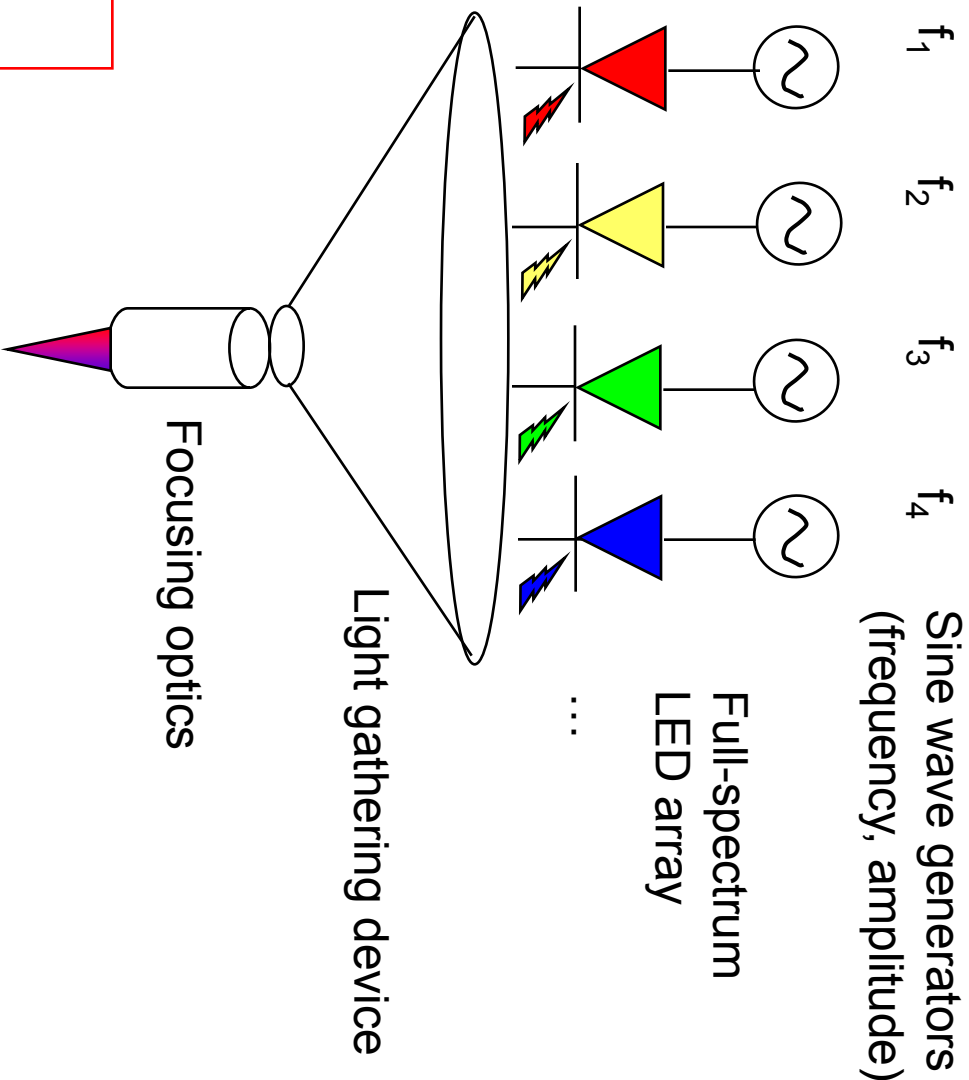


1000x decrease in time

New method: Real –Time Quantum Efficiency measurement system (RTQE)

Electronically-Controlled LED light source

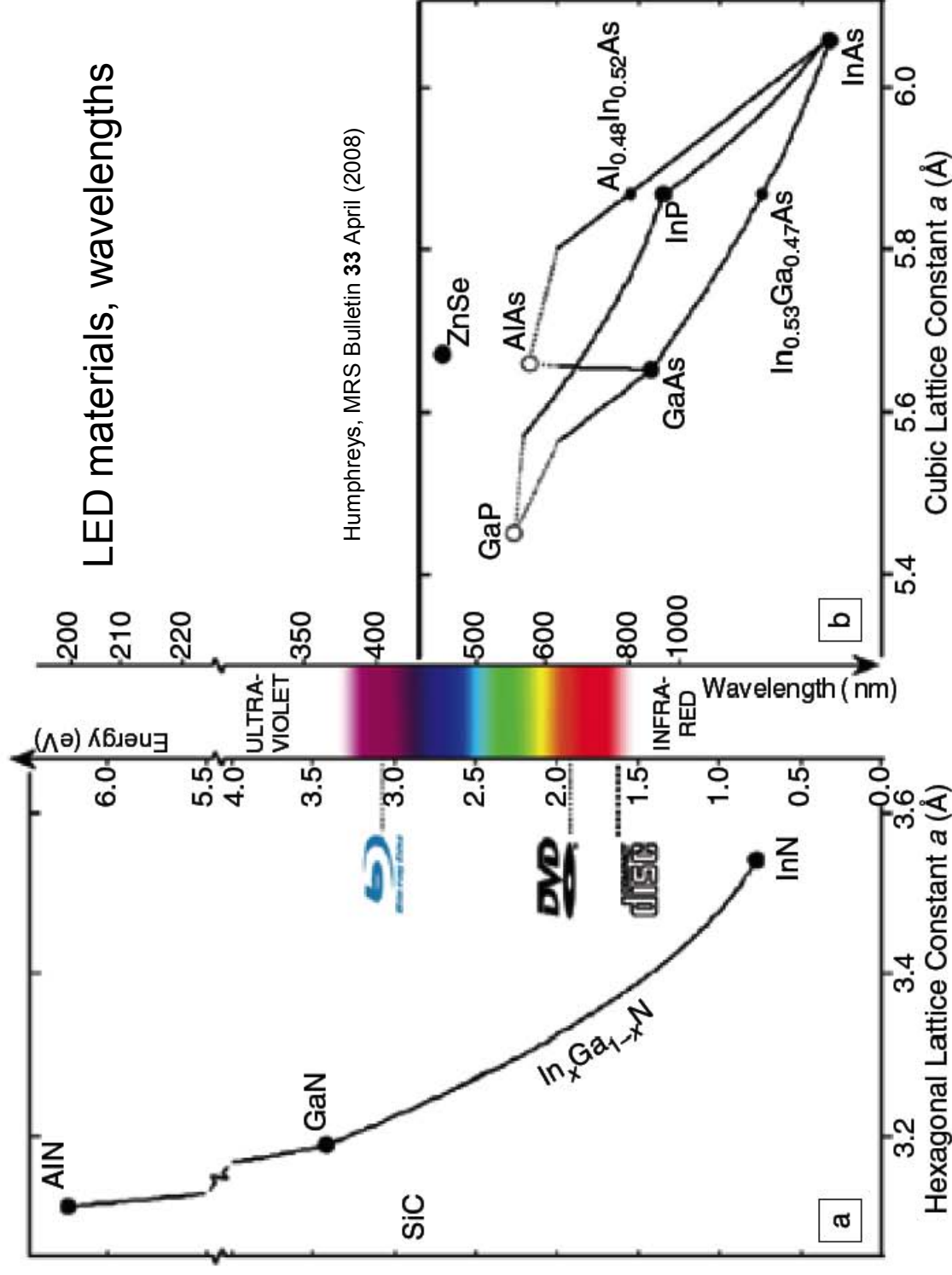
LED (#, color)	λ_{peak} (nm)	Drive- frequency (Hz)
1, Red	700	1000
2, Yellow	600	1153
3, Green	550	1262
4, Blue	470	875
...	-	-



Parallel processing of information from an array of spectral channels encoded in modulated frequency bands

New method: Real –Time Quantum Efficiency measurement system (RTQE)

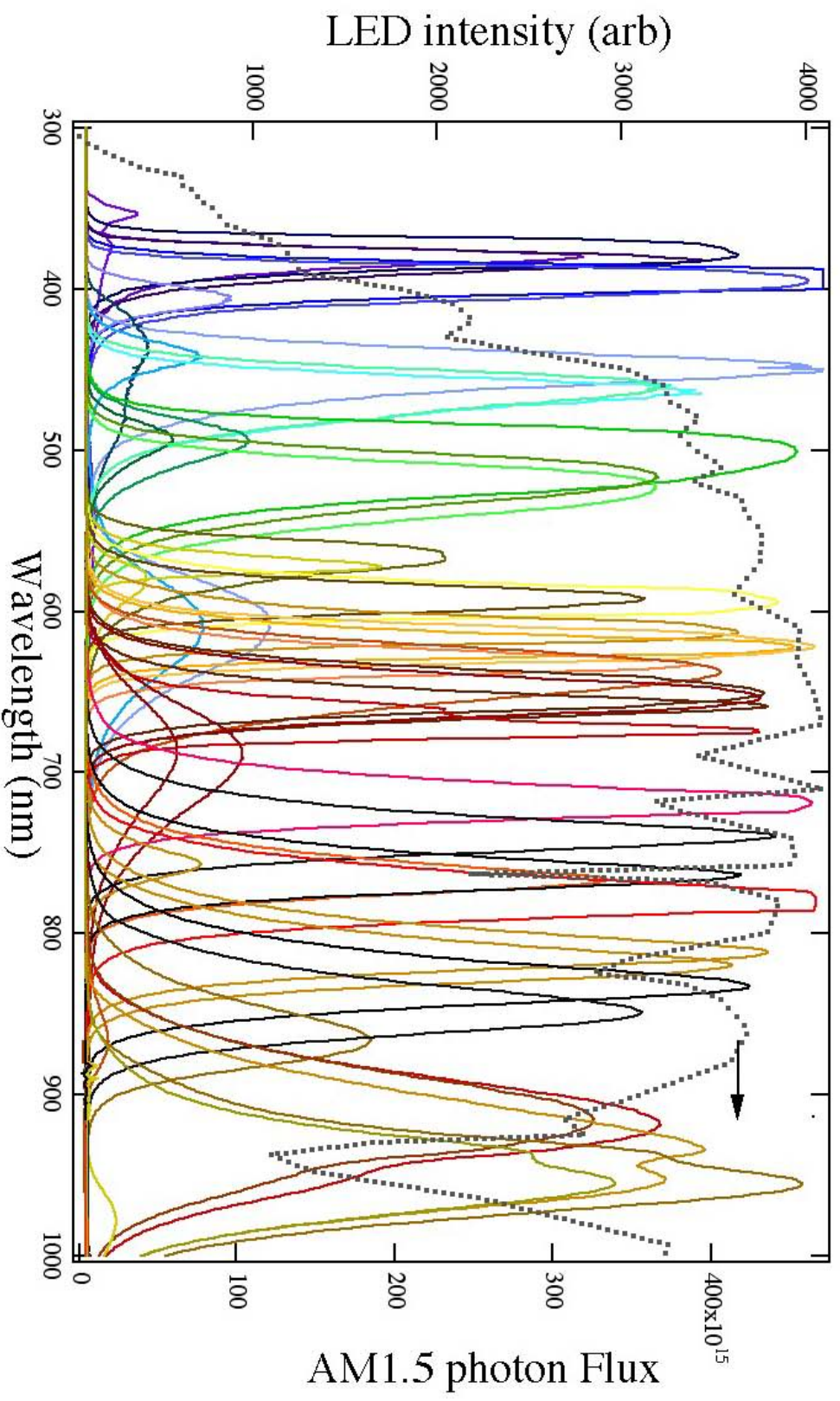
Electronically-Controlled LED light source



New method: Real – Time Quantum Efficiency measurement system (RTQE)

Electronically-Controlled LED light source

58-color LED array (2004)



Principle of operation

f, Sine wave drive frequency
 λ , LED emission wavelength

analog-to-digital
converter DAQ card

software

LED
(λ_{peak})
f
V

I
Current-to-voltage
preamp

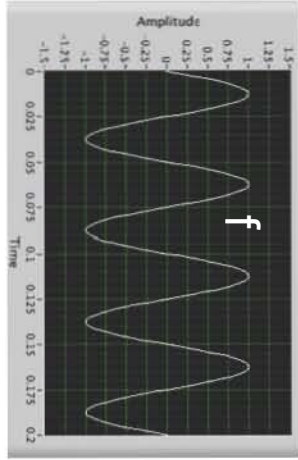
f_1 f_2 f_3 f_4



Current-to-voltage
preamp

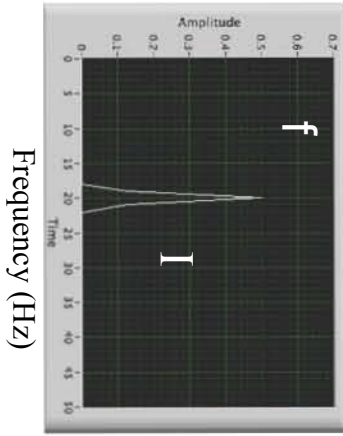


voltage vs time

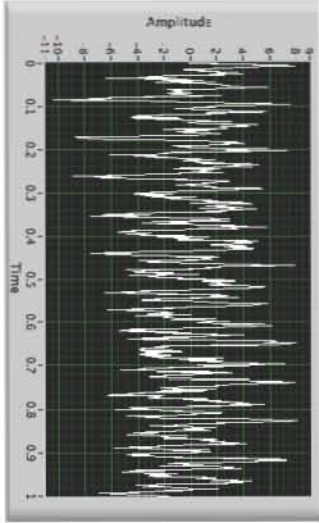


FFT

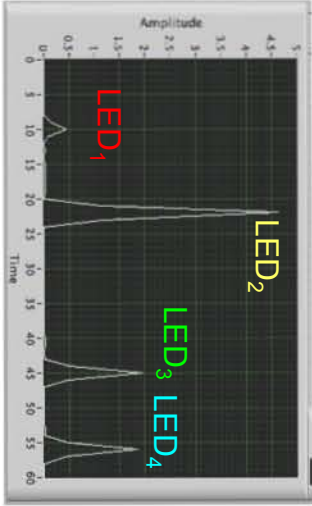
power spectrum



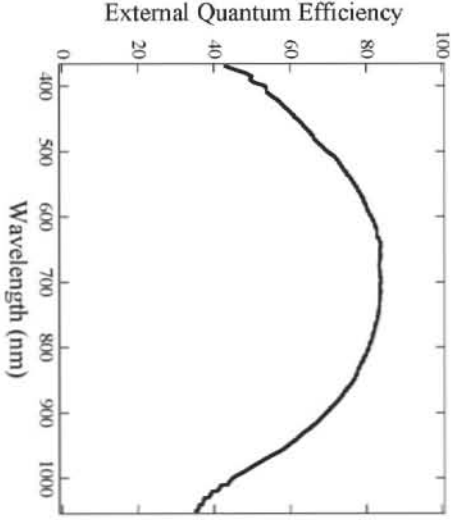
voltage vs time



FFT
power spectrum

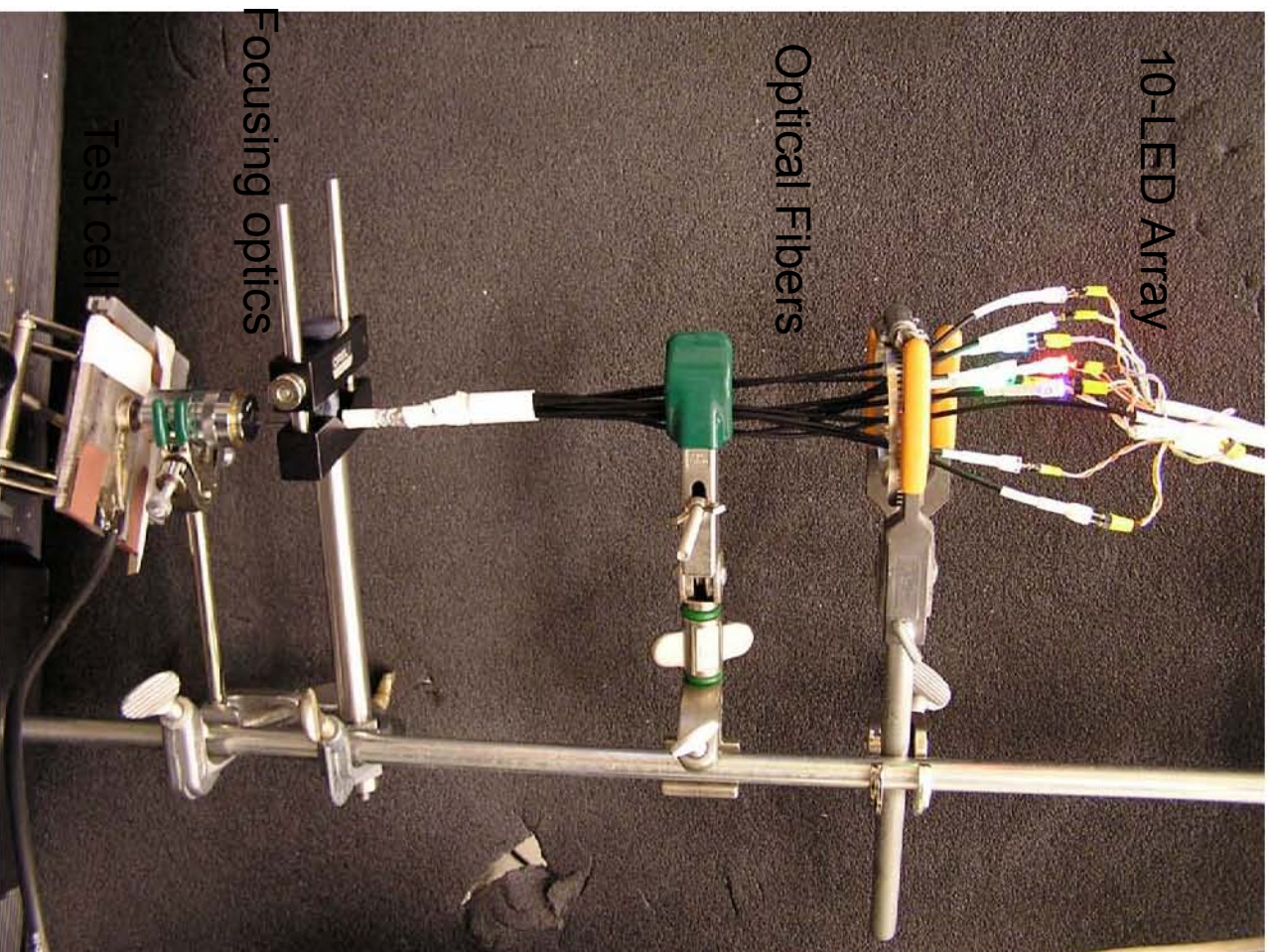


f_{λ} , $QE = K(I(f_{\lambda}))$

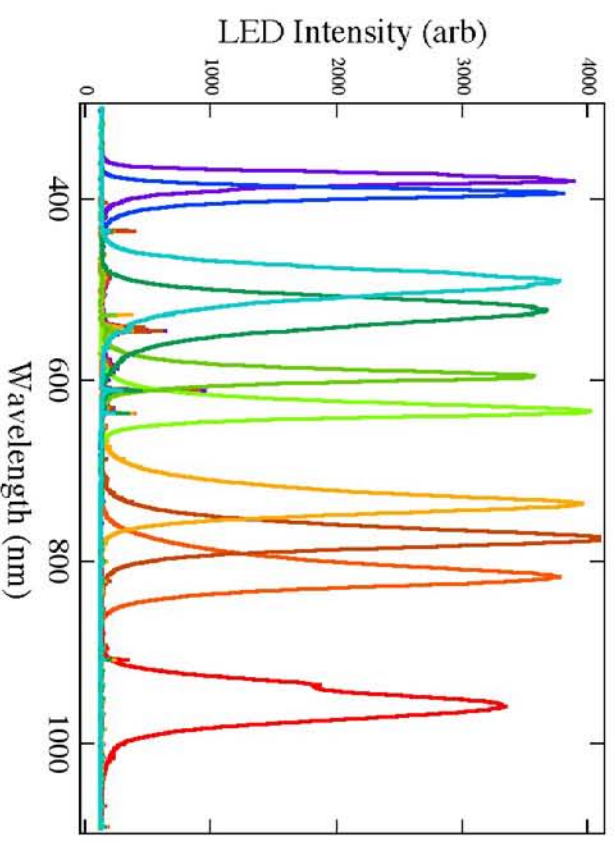


f_{λ_1} , $QE_1 = K_1(I(f_{\lambda_1}))$
 f_{λ_2} , $QE_2 = K_2(I(f_{\lambda_2}))$
 f_{λ_3} , $QE_3 = K_3(I(f_{\lambda_3}))$
 f_{λ_4} , $QE_4 = K_4(I(f_{\lambda_4}))$

Proof of concept: 10-LED Real-Time QE system prototype

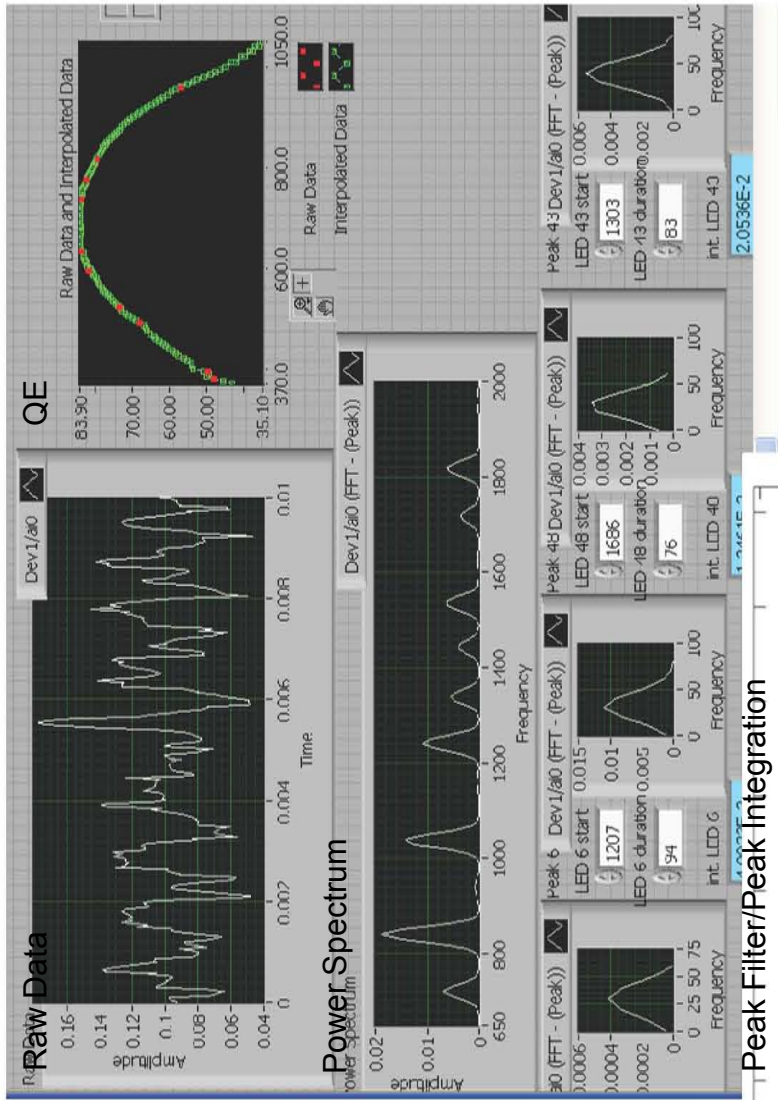


10 LEDs were chosen to span the Spectral response range of C-Si.

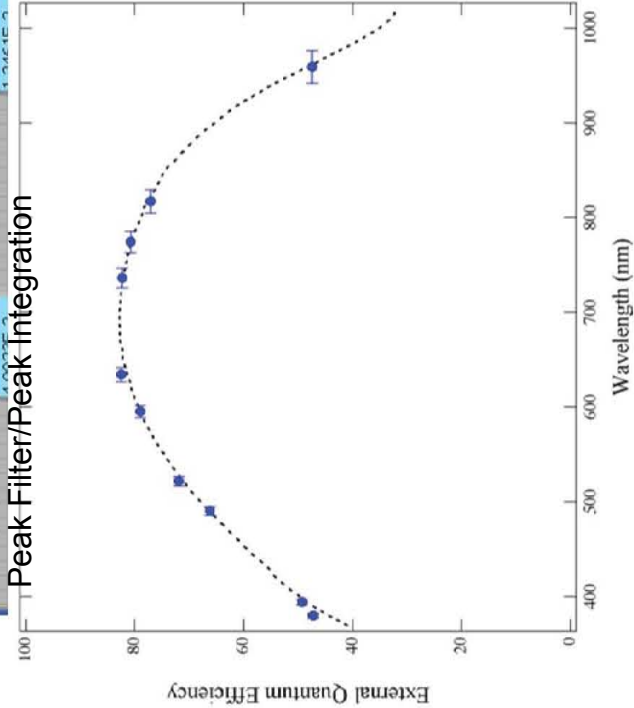


10-LED array prototype

f_1 f_2 f_3 f_4 f_5 f_6 f_7 f_8 f_9 f_{10}



Peak Filter/Peak Integration



LED QE (real-time)

Standard QE (20 mins)

Technical Considerations:

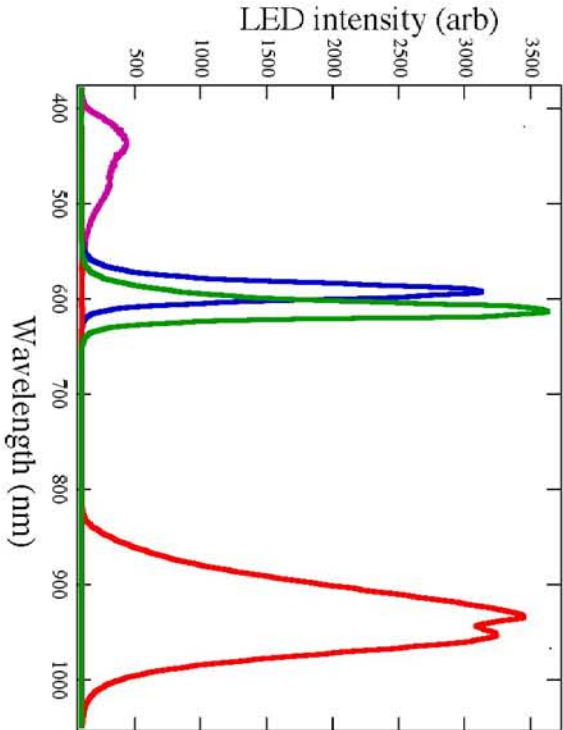
- 1) LED emission: Spectral width, Asymmetric spectra, Spectral overlap
Calibration accounts for LED spectra using Singular Value Decomposition mathematics

Singular Value Decomposition (SVD)
“least-squares-fit” for matrices

$$\text{Current (LED)} = \text{Illumination (LED, } \lambda) * \text{QE}(\lambda)$$

$$\begin{array}{ccc} \begin{array}{c} I_1 \\ I_2 \\ I_3 \\ \vdots \\ \vdots \\ \vdots \end{array} & \begin{array}{c} \text{LED spectrum} \\ \lambda_{11}, \lambda_{12}, \lambda_{13}, \dots \\ \lambda_{21}, \lambda_{22}, \lambda_{23}, \dots \\ \lambda_{31}, \lambda_{31}, \lambda_{33}, \dots \\ \dots \end{array} & \begin{array}{c} \text{QE} \\ \text{QE}_1 \\ \text{QE}_2 \\ \text{QE}_3 \\ \vdots \\ \vdots \\ \vdots \end{array} \\ = \text{LED \#} & * & \end{array}$$

$$(\text{QE}(\lambda)) = (V)(S)(U^T)(\text{current(LED)})$$



- 2) LED drive signal: sinusoidal LED emission, non-multiple drive frequencies.
high data acquisition < drive frequency < 1/response time

- 3) Data acquisition rate: 2x highest LED drive frequency (avoid aliasing)

The Real-Time QE system is:

Parallel processing of information from an array of spectral channels encoded in modulated frequency bands

- fast
- inexpensive
- all solid-state
- robust

- Replace traditional lab-based QE systems

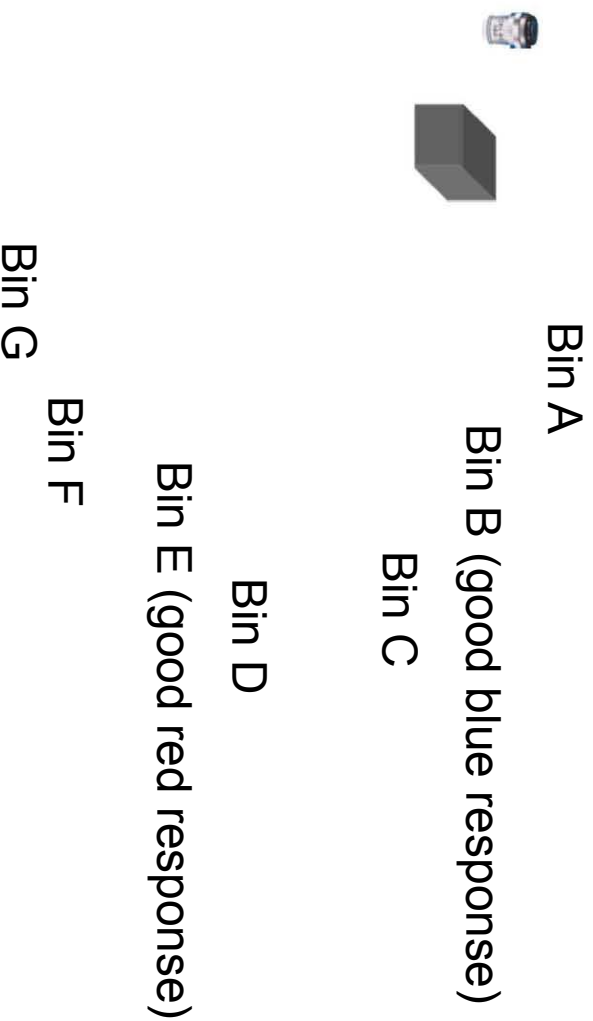
Expanded Applications

- In-line diagnostics
- Spatial QE mapping
- Multi-junction QE measurements

In-line QE for solar cell manufacturing

Benefits:

- In-line diagnostics for process control
- Device physics feedback
- Spectral-matching cell binning to maximize module KW-hr output



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Bin A

Bin B (good blue response)

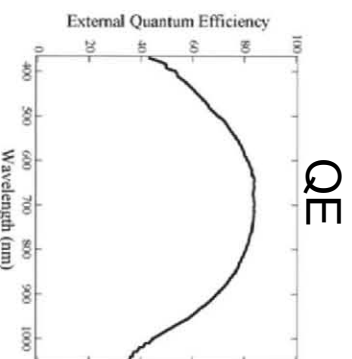
Bin C

Bin D

Bin E (good red response)

Bin F

Bin G



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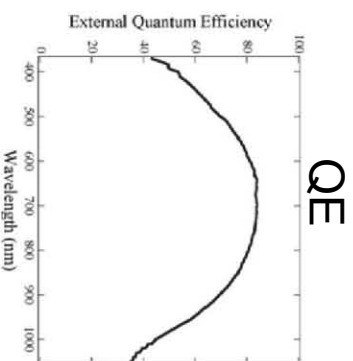
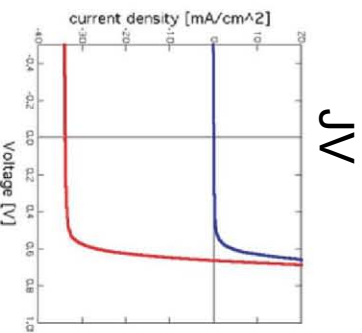
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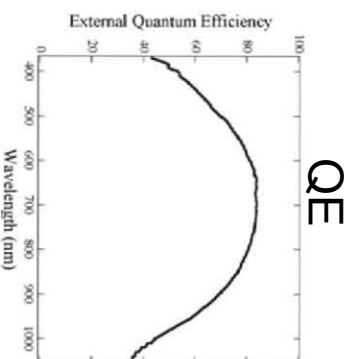
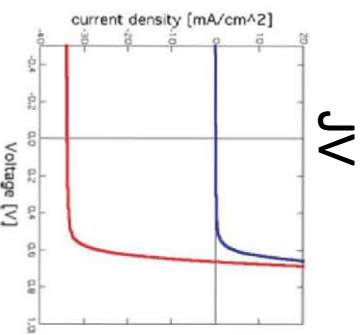
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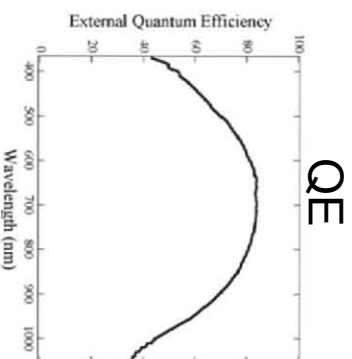
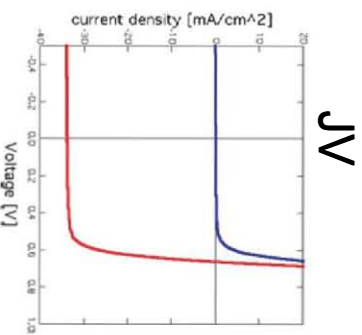
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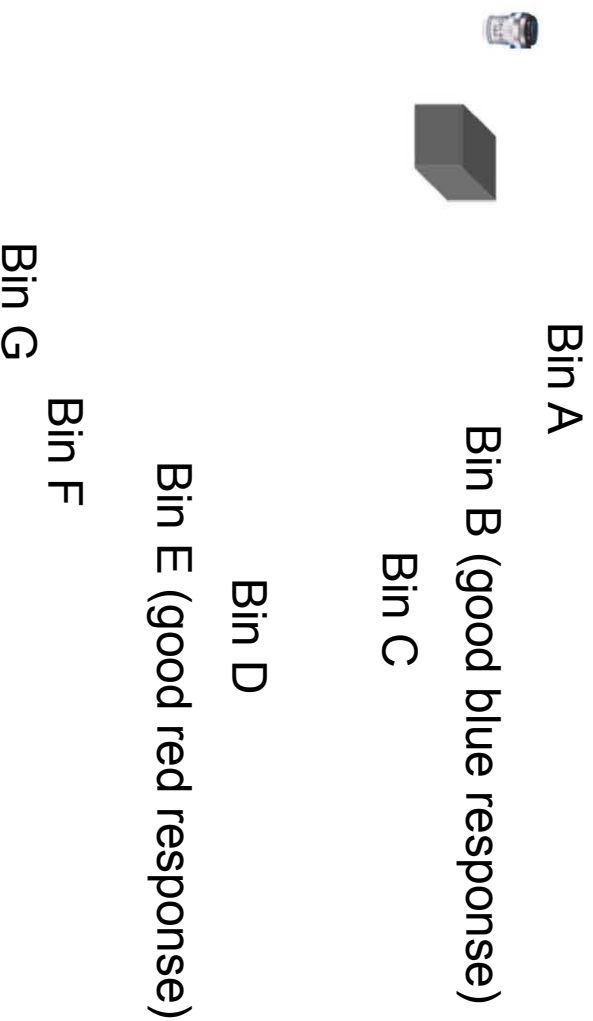
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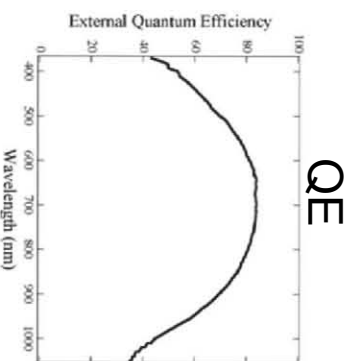
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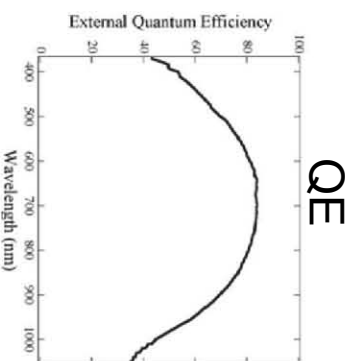
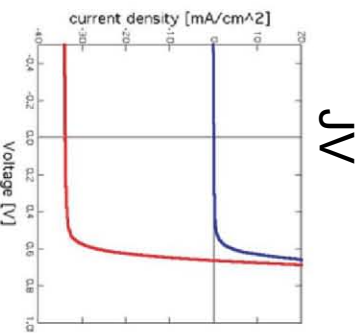
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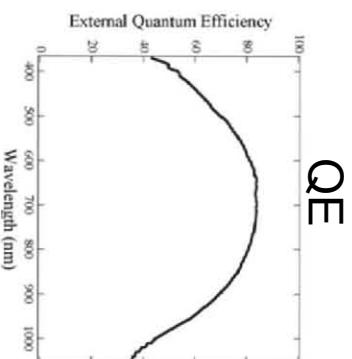
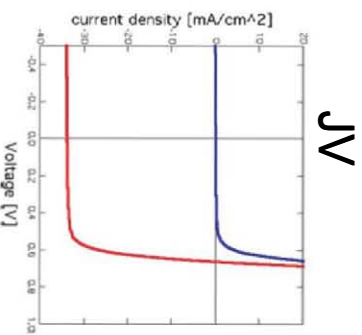
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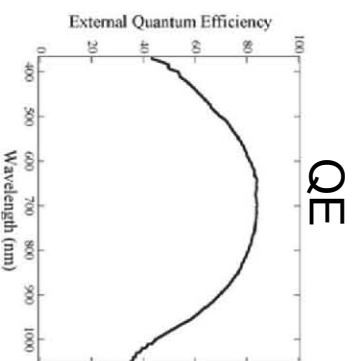
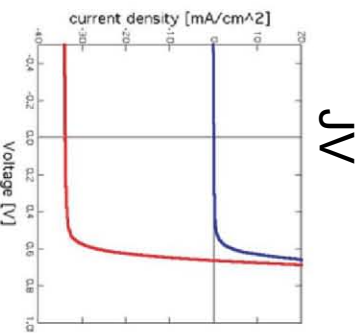
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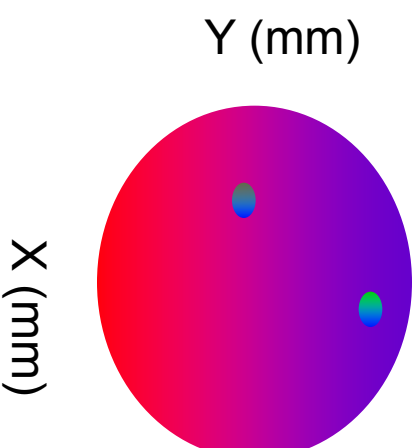
Bin E (good red response)

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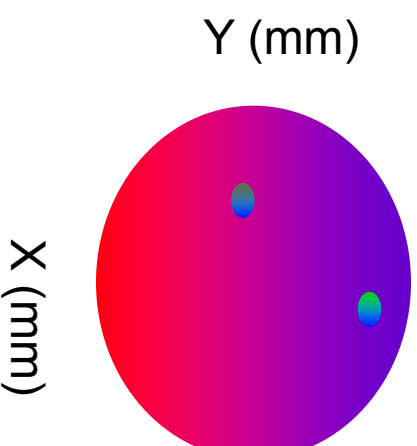


Spatial spectral-response Mapping (cells, modules)



Spatial spectral-response Mapping (cells, modules)

Cell and module uniformity
Defects
Process control





Real Time Quantum Efficiency Technique

- Electronically controlled full-spectrum LED light source
- Parallel data processing
- Simple, robust, “inexpensive”, solid-state, FAST (~ 1000 vs 1 QE Measurement during this talk)

Expanded Applications

- Industrial In-line diagnostics, spectral-matching cell sorting
- Spatial spectral response mapping
- Electronic filtering – tandem solar cell QE measurements
- Technique applicable to other spectroscopy techniques

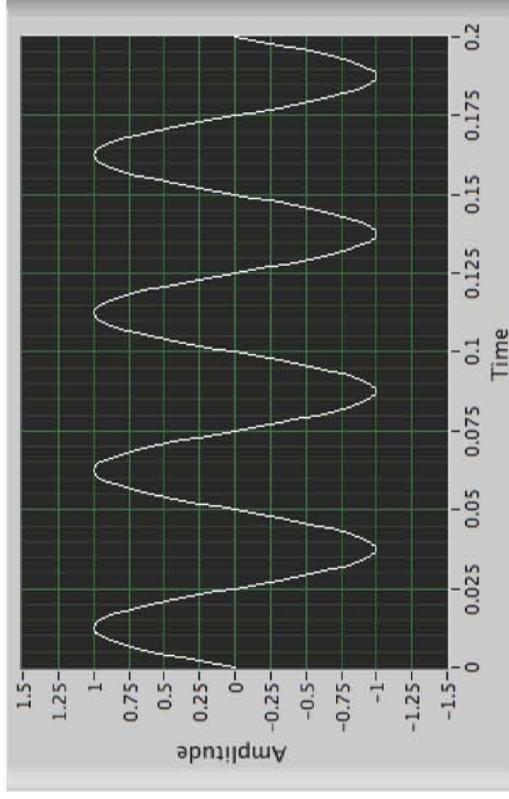
Further information:

Technical: david_young@nrel.gov

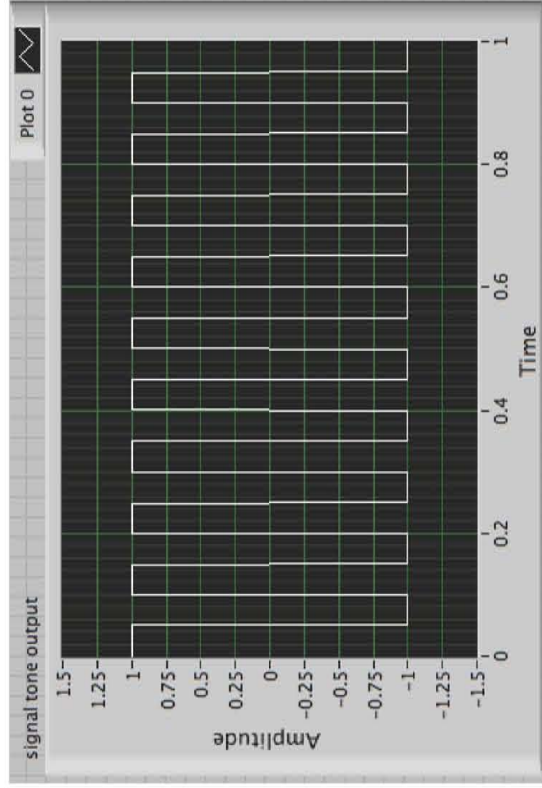
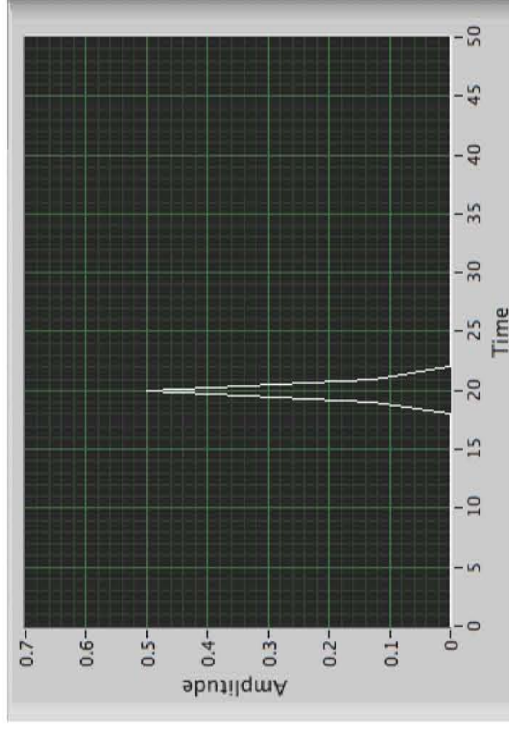
Technology Licensing: david_christensen@nrel.gov



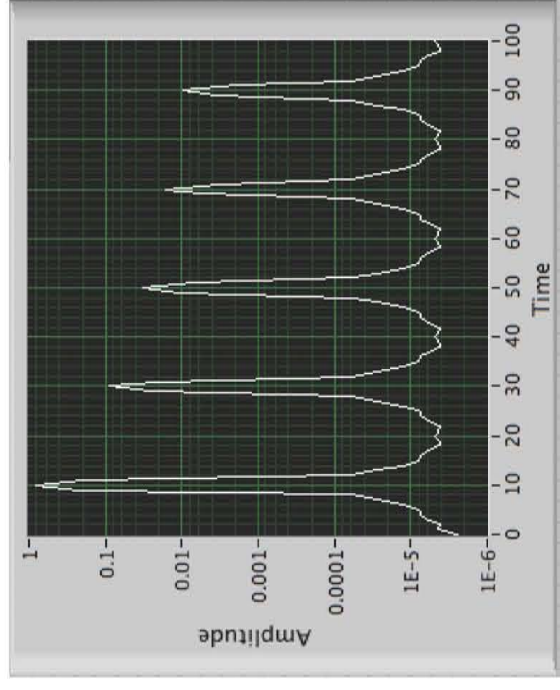
Pure sine wave drive voltage:



FFT



FFT



No multiple frequencies

fast data acquisition rate $< \text{Drive frequency} \times \text{minority life time} \times \text{acquisition}/2$

LED spectral width

